Special Issue

Deep Learning Approaches for Prenatal and Perinatal-Image Analysis

Message from the Guest Editors

Sensors welcomes submissions to this Special Issue on "Deep Learning Approaches for Prenatal and Perinatal-Image Analysis". The Special Issue topics include, but are not limited to:

- Obstetric ultrasound for diagnosis and biometric measurements
- RGB-D sensors for infants monitoring
- Intra-operative imaging for obstetric surgery (e.g., laparoscopy)
- Structure segmentation and classification
- Generative models
- Biometrics
- Challenges and datasets

Guest Editors

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Deadline for manuscript submissions

closed (10 October 2021)



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Sensors is a leading journal devoted to fast publication of the latest achievements of technological developments and scientific research in the huge area of physical, chemical and biochemical sensors, including remote sensing and sensor networks. Both experimental and theoretical papers are published, including all aspects of sensor design, technology, proof of concept and application. Sensors organizes Special Issues devoted to specific sensing areas and applications each year.

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